



# 16-BIT SYNCHRONOUS 2:1 MUX/DEMUX SWITCH

IDT74FST163232

## FEATURES:

- Bus switches provide zero delay paths
- Extended commercial range of  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$
- Low switch on-resistance
- TTL-compatible input and output levels
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- Available in SSOP, TSSOP, and TVSOP Packages
- Hot insertion capability
- Very low power dissipation

## DESCRIPTION:

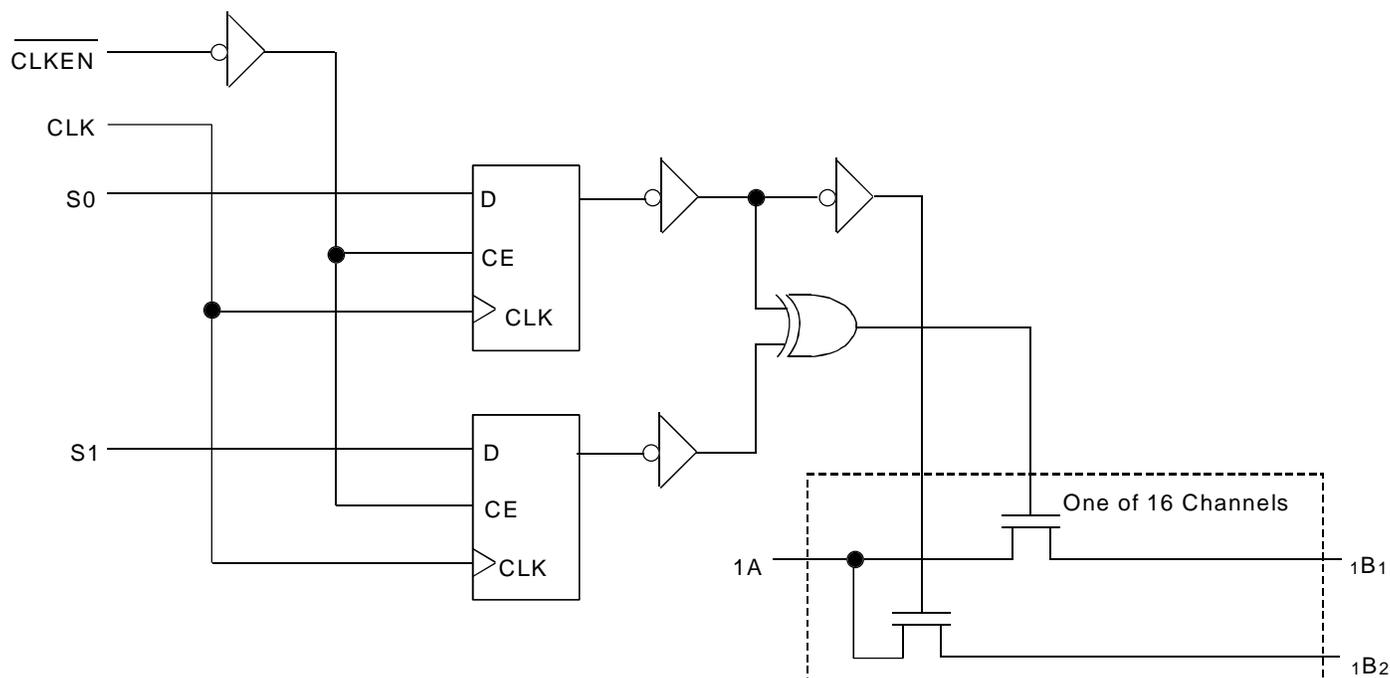
The FST163232 belong to IDT's family of Bus switches. Bus switch devices perform the function of connecting or isolating two ports without providing any inherent current sink or source capability. Thus they generate little or no noise of their own while providing a low resistance path for an external driver. These devices connect input and output ports through an n-channel FET. When the gate-to-source junction of this FET is adequately forward-biased the device conducts and the resistance between input and output ports is small. Without adequate bias on the gate-to-source junction of the FET, the FET is turned off, therefore with no VCC applied, the device has hot insertion capability.

The low on-resistance and simplicity of the connection between input and output ports reduces the delay in this path to close to zero.

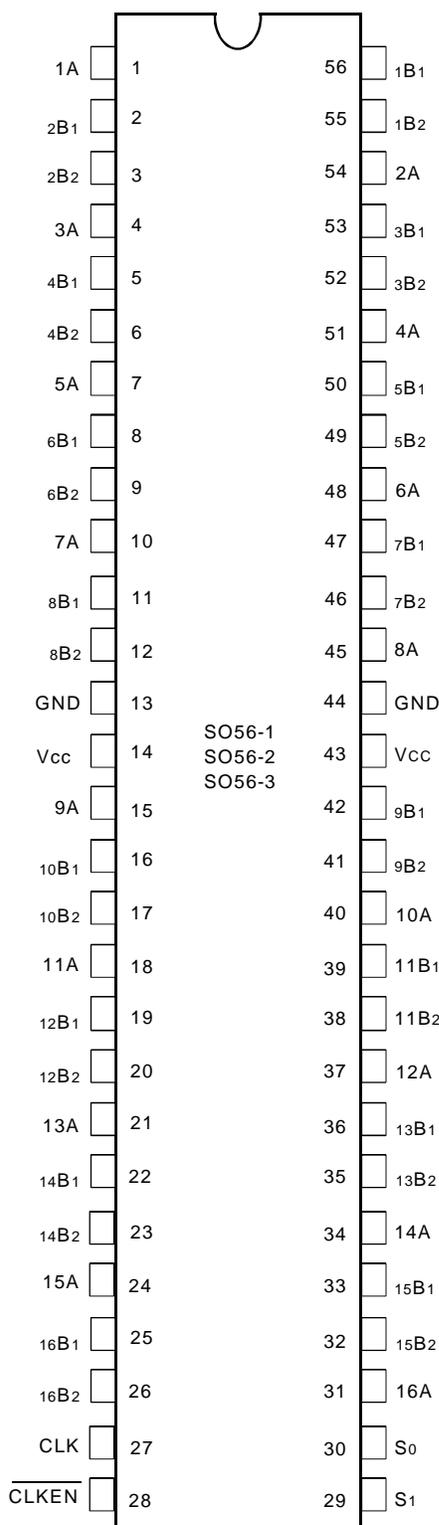
The FST163232 provides three 16-bit TTL-compatible ports that support 2:1 multiplexing. The S<sub>0,1</sub> pins control mux select and switch enable/disable. The S<sub>0,1</sub> inputs are synchronous and clocked on the rising edge of CLK when  $\overline{\text{CLKEN}}$  is low.

Port A can be connected to port B1 or port B2 or both ports B1 and B2.

## FUNCTIONAL BLOCK DIAGRAM



## PIN CONFIGURATION



SSOP/ TSSOP/ TVSOP  
TOP VIEW

## ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Rating	Max.	Unit
VTERM(2)	Terminal Voltage with Respect to GND	-0.5 to +7	V
TSTG	Storage Temperature	-65 to +150	°C
IOUT	Maximum Continuous Channel Current	128	mA

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### NOTES:

- Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- Vcc, Control, and Switch terminals.

## CAPACITANCE (1)

Symbol	Parameter	Conditions(2)	Typ.	Unit
CIN	Control Input Capacitance		6	pF
C <sub>I/O</sub>	Switch Input/Output Capacitance, A Port	Switch Off	17	pF
C <sub>I/O</sub>	Switch Input/Output Capacitance, B Port	Switch Off	12	pF

### NOTES:

- Capacitance is characterized but not tested.
- T<sub>A</sub> = 25°C, f = 1MHz, V<sub>IN</sub> = 0V, V<sub>OUT</sub> = 0V

## PIN DESCRIPTION

Pin Names	I/O	Description
A	I/O	Bus A
B1, B2	I/O	Buses B1, B2
S <sub>0,1</sub>	I	Control Pins
CLK	I	Clock Input. Clocks S <sub>0,1</sub> on Rising Edge
CLKEN	I	Clock Enable Input

## FUNCTION TABLE (1)

S <sub>1</sub>	S <sub>0</sub>	CLK	CLKEN	Description
X	X	X	H	Last state
L	L	↑	L	Disconnect
L	H	↑	L	A to B1 and A to B2
H	L	↑	L	A to B1 or B1 to A
H	H	↑	L	A to B2 or B2 to A

### NOTE:

- H = HIGH Voltage level  
L = LOW Voltage Level  
X = Don't Care  
↑ = Low-to-High Transition

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Conditions:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions	Min.	Typ. <sup>(1)</sup>	Max.	Unit
$V_{IH}$	Control Input HIGH Voltage	Guaranteed Logic HIGH for Control Inputs	2	—	—	V
$V_{IL}$	Control Input LOW Voltage	Guaranteed Logic LOW for Control Inputs	—	—	0.8	V
$I_{IH}$	Control Input HIGH Current	$V_{CC} = \text{Max.}$ $V_I = V_{CC}$ $V_I = \text{GND}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{IL}$	Control Input LOW Current		—	—	$\pm 1$	
$I_{OZH}$	Current during	$V_{CC} = \text{Max.}$ , $V_O = 0$ to $5\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{OZL}$	Bus Switch DISCONNECT		—	—	$\pm 1$	
$V_{IK}$	Clamp Diode Voltage	$V_{CC} = \text{Min.}$ , $I_{IN} = -18\text{mA}$	—	-0.7	-1.2	V
$I_{OFF}$	Switch Power Off Leakage	$V_{CC} = 0\text{V}$ , $V_{IN}$ or $V_O \leq 5.5\text{V}$	—	—	$\pm 1$	$\mu\text{A}$
$I_{CC}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}$ , $V_{IN} = \text{GND}$ or $V_{CC}$	—	0.1	3	$\mu\text{A}$

FST LINK

## BUS SWITCH IMPEDANCE OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Conditions:  $T_A = -40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

Symbol	Parameter	Test Conditions	Min.	Typ. <sup>(1)</sup>	Max.	Unit
$R_{ON}$	Switch On Resistance <sup>(2)</sup>	$V_{CC} = \text{Min.}$ , $V_{IN} = 0\text{V}$ $I_{ON} = 64\text{mA}$	—	4	7	$\Omega$
		$V_{CC} = \text{Min.}$ , $V_{IN} = 0\text{V}$ $I_{ON} = 30\text{mA}$	—	4	7	$\Omega$
		$V_{CC} = \text{Min.}$ , $V_{IN} = 2.4\text{V}$ $I_{ON} = 15\text{mA}$	—	6	15	$\Omega$
$I_{OS}$	Short Circuit Current, A to B <sup>(3)</sup>	$A(B) = 0\text{V}$ , $B(A) = V_{CC}$	100	—	—	$\text{mA}$

### NOTES:

1. Typical values are at  $V_{CC} = 5.0\text{V}$ ,  $+25^{\circ}\text{C}$  ambient.
2. The voltage drop between the indicated ports divided by the current through the switch.
3. Not more than one output should be shorted at one time. Duration of the test should not exceed one second.

## POWER SUPPLY CHARACTERISTICS

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$\Delta I_{CC}$	Quiescent Power Supply Current TTL Inputs HIGH	V <sub>CC</sub> = Max. V <sub>IN</sub> = 3.4V <sup>(3)</sup>		—	0.5	1.5	mA
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>(4, 5)</sup>	V <sub>CC</sub> = Max. Clock Pin Toggling 50% Duty Cycle 16 Switches Toggling One Select Toggling at 50% of CLK frequency	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND				μA/ MHz/
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>(4, 5)</sup>	V <sub>CC</sub> = Max. Clock Pin Toggling 50% Duty Cycle 16 Switches Toggling One Select Toggling at 50% of CLK frequency	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND				μA/ MHz/
I <sub>CCD</sub>	Dynamic Power Supply Current <sup>(4, 5)</sup>	V <sub>CC</sub> = Max. Clock Pin Toggling 50% Duty Cycle 32 Switches Toggling 2 Select Pins Toggling at 50% of CLK frequency	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND				μA/ MHz/
I <sub>C</sub>	Total Power Supply Current <sup>(6)</sup>	V <sub>CC</sub> = Max. f <sub>CP</sub> = 10MHz (CLK) 50% Duty Cycle CLKEN = LOW S0 = HIGH or LOW fi = 2.5MHz (S1) 16 Switches Toggling	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND				mA
		V <sub>CC</sub> = Max. f <sub>CP</sub> = 10MHz (CLK) 50% Duty Cycle CLKEN = LOW S1 = HIGH fi = 2.5MHz (S0) 16 Muxes Exchanging	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = 3.4V				
		V <sub>CC</sub> = Max. f <sub>CP</sub> = 10MHz (CLK) 50% Duty Cycle CLKEN = LOW S1 = HIGH fi = 2.5MHz (S0) 16 Muxes Exchanging	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = GND				
		V <sub>CC</sub> = Max. f <sub>CP</sub> = 10MHz (CLK) 50% Duty Cycle CLKEN = LOW S1 = LOW fi = 2.5MHz (S0) 32 Switches Toggling	V <sub>IN</sub> = V <sub>CC</sub> V <sub>IN</sub> = 3.4V				

### NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type. T<sub>A</sub> = -40°C to +85°C
- Typical values are at V<sub>CC</sub> = 5.0V, +25°C ambient.
- Per TTL driven input (V<sub>IN</sub> = 3.4V). All other inputs at V<sub>CC</sub> or GND. Switch inputs do not contribute to  $\Delta I_{CC}$ .
- This parameter represents the current required to switch the internal capacitance of the control inputs at the specified frequency. Switch inputs generate no significant power supply currents as they transition. This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- C<sub>PD</sub> = I<sub>CCD</sub>/V<sub>CC</sub>  
C<sub>PD</sub> = Power Dissipation Capacitance
- I<sub>C</sub> = I<sub>QUIESCENT</sub> + I<sub>INPUTS</sub> + I<sub>DYNAMIC</sub>  
I<sub>C</sub> = I<sub>CC</sub> +  $\Delta I_{CC}$  D<sub>H</sub>N<sub>T</sub> + I<sub>CCD</sub> (fiN)  
I<sub>CC</sub> = Quiescent Current  
 $\Delta I_{CC}$  = Power Supply Current for a TTL High Input (V<sub>IN</sub> = 3.4V)  
D<sub>H</sub> = Duty Cycle for TTL Inputs High  
N<sub>T</sub> = Number of TTL Inputs at D<sub>H</sub>  
I<sub>CCD</sub> = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)  
fi = Control Input Frequency  
N = Number of Control Inputs Toggling at fi

## SWITCHING CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Conditions:  $T_A = -40^\circ\text{C}$  to  $+85^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V} \pm 10\%$

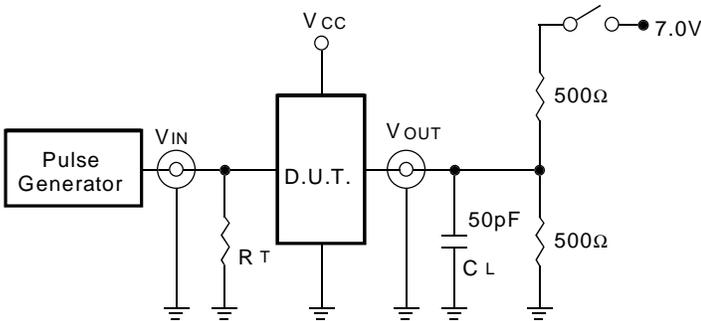
Symbol	Description <sup>(1)</sup>	$V_{CC} = 5\text{V} \pm 10\%$			$V_{CC} = 4\text{V}$		Unit
		Min.	Typ.	Max.	Min.	Max.	
t <sub>PLH</sub> t <sub>PHL</sub>	Data Propagation Delay A to B, B to A <sup>(2)</sup>	—	—	0.25	—	0.25	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Switch CONNECT Delay CLK $\uparrow$ to A-B1 or A-B2	1.5	—	5.8	—	6.1	ns
t <sub>PZH</sub> t <sub>PZL</sub>	Switch CONNECT Delay CLK $\uparrow$ to B1-B2	1.5	—	7.9	—	8.5	ns
t <sub>PHZ</sub> t <sub>PLZ</sub>	Switch DISCONNECT Delay CLK $\uparrow$ to A, B	1.9	—	6.2	—	5.8	ns
t <sub>BX</sub>	Switch EXCHANGE Delay CLK $\uparrow$ from A-B1 (B2) to A-B2 (B1)	1.8	—	6.2	—	6.8	ns
t <sub>SU</sub>	Clock Enable Set-Up Time $\overline{\text{CLKEN}}$ to CLK $\uparrow$	1.9	—	—	2.2	—	ns
t <sub>H</sub>	Clock Enable Hold Time $\overline{\text{CLKEN}}$ after CLK $\uparrow$	1	—	—	1.9	—	ns
t <sub>SU</sub>	Select Set-Up Time S <sub>0</sub> , S <sub>1</sub> to CLK $\uparrow$	1.9	—	—	2.2	—	ns
t <sub>H</sub>	Select Hold Time S <sub>0</sub> , S <sub>1</sub> after CLK $\uparrow$	1	—	—	0.5	—	ns
Q <sub>CI</sub>	Charge Injection During Switch DISCONNECT, CLK $\uparrow$ to A, B <sup>(3)</sup>	—	1.5	—	—	—	pC
Q <sub>DCI</sub>	Charge Injection During Switch DISCONNECT, CLK $\uparrow$ to A, B <sup>(3)</sup>	—	0.5	—	—	—	

### NOTES:

1. See test circuits and waveforms.
2. The bus switch contributes no Propagation Delay other than the RC Delay of the load interacting with the RC of the switch.
3. |Q<sub>CI</sub>| is the charge injection for a single switch DISCONNECT and applies to either single switches or multiplexers.  
|Q<sub>DCI</sub>| is the charge injection for a multiplexer as the multiplexed port switches from one path to another. Charge injection is reduced because the injection from the DISCONNECT of the first path is compensated by the CONNECT of the second path.

## TEST CIRCUITS AND WAVEFORMS

### TEST CIRCUITS FOR ALL OUTPUTS



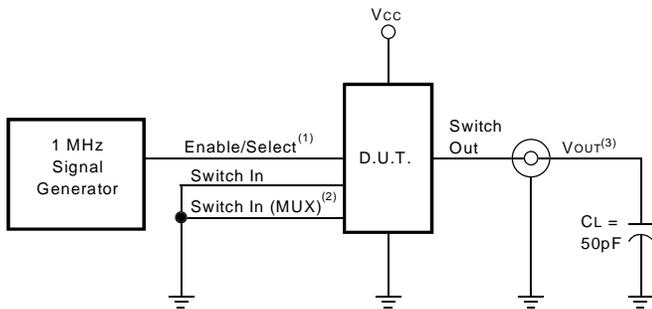
### SWITCH POSITION

Test	Switch
Open Drain	Closed
Disable Low	
Enable Low	
All Other Tests	Open

#### DEFINITIONS:

$C_L$  = Load capacitance: includes jig and probe capacitance.  
 $R_T$  = Termination resistance: should be equal to  $Z_{OUT}$  of the Pulse Generator.

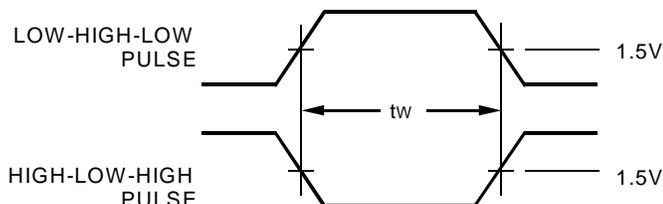
### CHARGE INJECTION



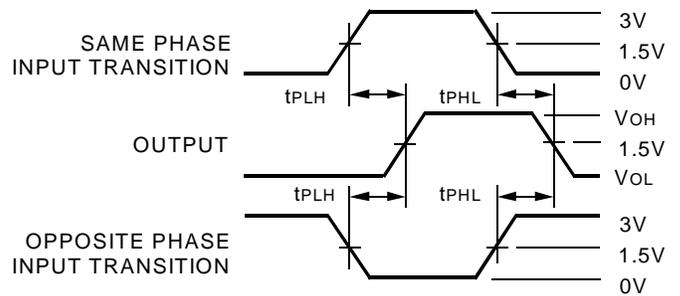
#### NOTES:

- Select is used with multiplexers for measuring  $I_{QDCIL}$  during multiplexer select. During all other tests Enable is used.
- Used with multiplexers to measure  $I_{QDCIL}$  only.
- Charge Injection =  $\Delta V_{OUT} C_L$ , with Enable toggling for  $I_{QDCIL}$  or Select toggling for  $I_{QDCIL}$ .  $\Delta V_{OUT}$  is the change in  $V_{OUT}$  and is measured with a 10MΩ probe.

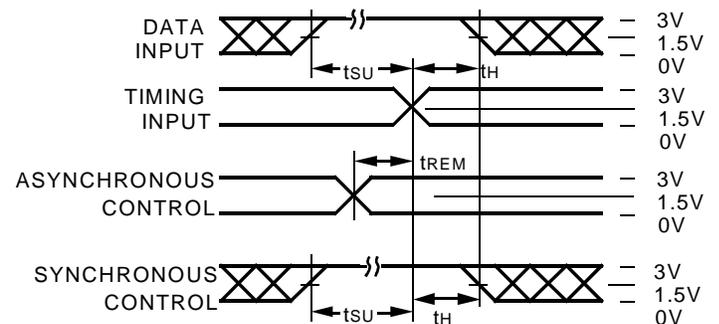
### PULSE WIDTH



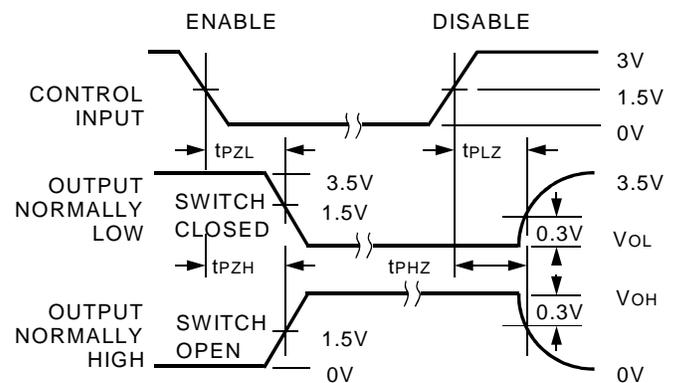
### PROPAGATION DELAY



### SET-UP, HOLD, AND RELEASE TIMES



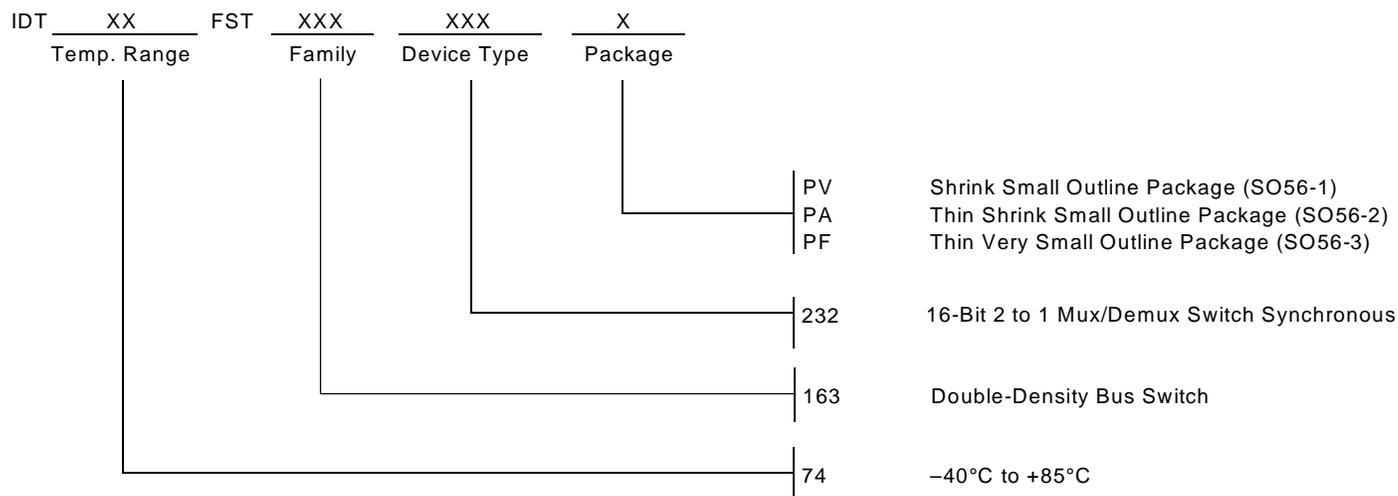
### ENABLE AND DISABLE TIMES



#### NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate  $\leq 1.0\text{MHz}$ ;  $t_f \leq 2.5\text{ns}$ ;  $t_r \leq 2.5\text{ns}$

**ORDERING INFORMATION**



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 800-345-7015 or 408-727-6116  
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